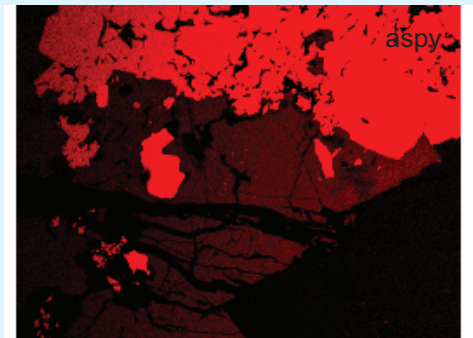
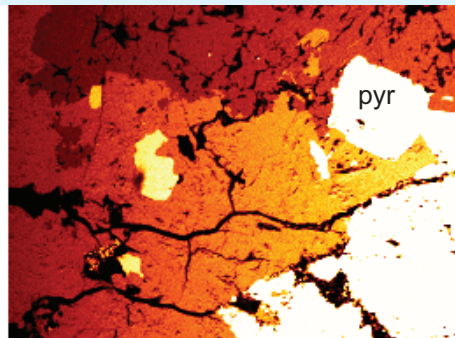
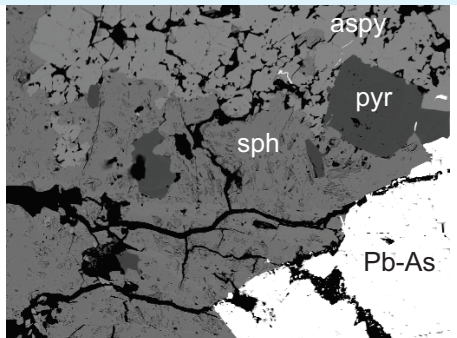


Scanning Electron Microscope / Electron Probe Micro-analysis

Chemical mapping applications

X-rays generated by scanning an electron beam across a sample can be used to produce chemical maps for both major and trace elements. In this example, the different phases shown on the back-scattered electron image can be identified by element mapping. Thus the distribution of sphalerite (sph: Zn-rich), arsenopyrite (aspy: As-Fe-S), pyrite (pyr: Fe-S) and a Pb-As sulphosalt (Pb-As) is clear.



Back-scattered image

